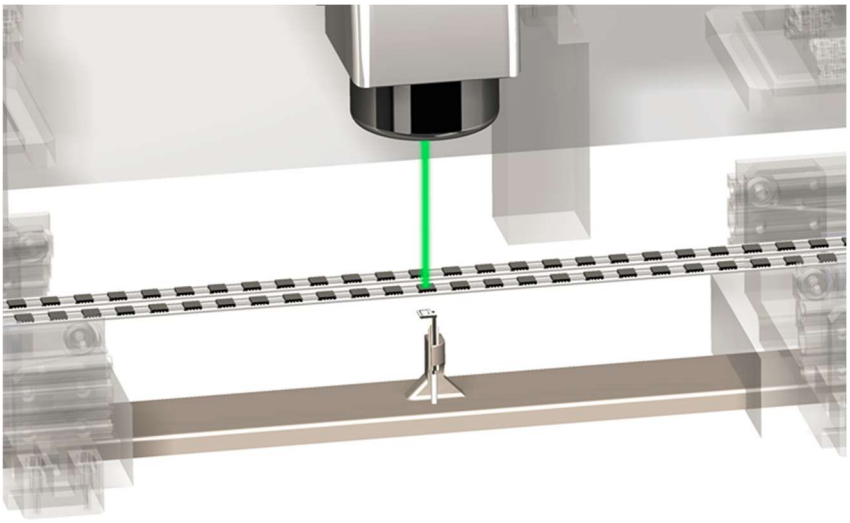
Microelectronics Inspection with Laser Microphone

Unique laser-based microphone technology enables the ultrasonic NDT inspection of semiconductor components without any contact, water or coupling liquid. The semiconductor test equipment is available as a stand-alone desktop tool for semiconductor testing in fail labs and R&D laboratories and can also be integrated into a high-volume production line to enable 100% quality control.



The desktop station offers two operation modes: a high-speed, non-contact imaging mode, and the ultrafast single-shot quality control mode. Both modes enable electronic chip testing by offering non-contact, non-destructive detection of delamination and other internal defects. In the imaging mode, these defects can be located and analyzed in detail, while the single-shot mode offers unparalleled speed with up to 1000 components inspected per second. Utilizing the Laser Microphone‘s technology increases your productivity in failure analysis and greatly improves reliability in production!

Features

- Compact and highly versatile desktop tool or fully automated inline inspection
- 100% documented safety for your customer with the inline inspection system
- Unique non-contact sensor technology without contact, water or coupling liquids
- No interference with other production steps
- High-speed imaging mode with up to 10.000 imaging points per second
- Single-shot inspection mode for up to 1.000 samples per second
- Combination with offline non-contact imaging of defective components for further analysis possible

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